

ReticleSense® Airborne Particle Sensor Quartz (APSRQ)

APSRQ

- **Improve equipment set-up and long term yields by wirelessly monitoring airborne particles in real-time.**

Quickly monitors, identifies and enables troubleshooting of airborne particles down to 0.14um within semiconductor process equipment and automated material handling systems.

- **Ideal for use in FAB scanners and steppers that read barcodes and alignment in transmission.**



Speed equipment qualification with wireless measurements.

- Collect and display particle data wirelessly using the APSRQ and Particle View™ software for real-time equipment diagnostics.
- Compare past to present as well as one tool to another with recorded particle data.
- Save time by swiftly locating contamination sources with the APSRQ data and see the effect of cleanings, adjustments and repairs in real time.

Shorten equipment maintenance cycles with reticle-like form factor.

- Detect particles in real-time without opening the tool so you don't need to expose process areas to the environment.
- APSRQ goes where reticles go to find the place where particles contaminate reticles.
- Once the location of particles is identified, tools may be selectively cleaned. Open only the dirty portion, keep the clean areas clean.

Lower equipment expenses with objective and reproducible data.

- Raise your first-pass monitor reticle success, reduce your qualification expense and increase availability with APSRQ.
- Receive early warning for impending equipment failures and optimize your preventative maintenance plans.
- Establish a baseline from known clean tool, then cycle APSRQ through a candidate tool before committing monitor reticles.

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of the ReticleSense APSRQ – The most efficient and effective wireless measurement device for airborne particles.

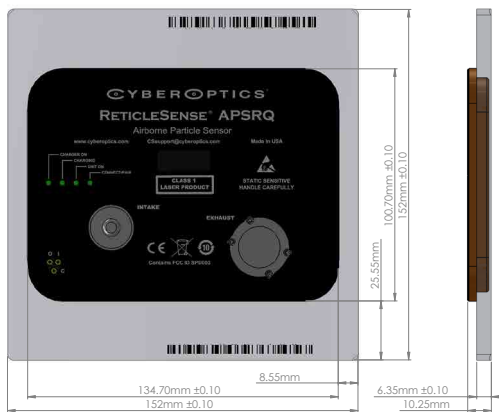


Save Time. Save Expense. Improve Yields.

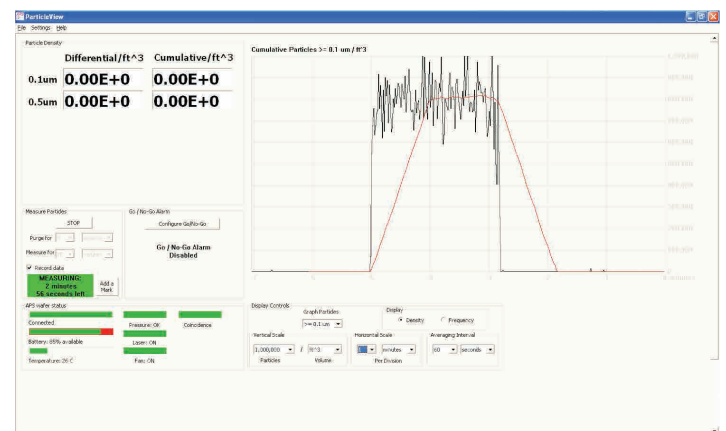
Features*

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| Wireless, reticle-shaped and battery-powered | Available in 6 inch Reticle form factor |
| Easy-to-use software | ParticleView and ParticleReview software included ParticleView: Displays real-time numeric and visual feedback, cumulative or differential counting modes and density or frequency modes ParticleReview: Replays log file data for review and analysis |
| Highly accurate | Measures particles greater than 0.14µm Size channels: Reports particles in 0.1 µm and 0.5µm bin sizes and larger particles in 2, 5, 10 and 30 µm bin sizes. |
| Durable housing | Quartz outer frame: Rear surface of quartz frame is an uninterrupted quartz surface |
| Weight | 312g (+/- 15g) |
| Barcodes and Alignment | Bar codes and alignment marks allow placement in most scanners and steppers |
| Airflow | 0.07CFM (2L/min) @ 1 atmosphere |
| Operating pressure | 0.4 to 1.6 atmosphere |
| Operating internal temperature | 15 deg C to 45 deg C non-condensing |
| Battery-operation | >1 hour per charge. Inductive wireless charging and handsfree operation. |
| WaferSense Link | Bluetooth, Class 1, 2.4 GHz |
| Operating Systems | Windows 7, 8, 10, XP, Vista |
| Product components | Particle measurement device, charging clean case, carrying suitcase, USB communications link module and application software |
| Calibration | Factory recalibration recommended annually |

Dimensions



ParticleView™



Real-time data.



Contact CyberOptics today for your complimentary on-tool demonstration
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